

Notice of References Cited	Application/Control No. 10/065,554	Applicant(s)/Patent Under Reexamination HUNG ET AL.	
	Examiner Thao X Le	Art Unit 2814	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0153546	10-2002	Verhaar, Robertus Dominicus Joseph	257/296
	B	US-2003/0068859	04-2003	Leung et al.	438/257
	C	US-2002/0074592	06-2002	Abedifard, Ebrahim	257/315
	D	US-5,741,735	04-1998	Violette et al.	438/279
	E	US-5,225,698	07-1993	Kim et al.	257/303
	F	US-2002/0175394	11-2002	Wu et al.	257/510
	G	US-2003/0031068	02-2003	Yuan et al.	365/200
	H	US-2003/0122181	07-2003	Wu, Ching-Yuan	257/315
	I	US-2003/0143790	07-2003	Wu, Ching-Yuan	438/197
	J	US-5,834,807	11-1998	Kim, Keon-soo	257/315
	K	US-6,628,544	09-2003	Shum et al.	365/185.03
	L	US-6,534,817	03-2003	Hsu et al.	257/314
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.